## Amendments to the Claims:

The following listing of claims will replace all prior versions, and listings, of claims in the application:

- 1-9. (Canceled)
- 10. (Currently Amended) An abrasive for polishing a substrate comprising silica in an amount of 50 wt% or more, the abrasive comprising a sol includingsol, which includes particles dispersed in an aqueous medium, wherein:

the particles comprise as a main component crystalline cerium oxide of cubic system and as an additional component a lanthanum compound, neodymium compound or a combination thereof;

the additional component is contained in an X/(Ce + X) molar ratio of 0.005 to 0.15 in which X is lanthanum atoms, neodymium atoms or a combination thereof;

the particles are present in the abrasive in an amount of 0.1 to 50 wt%; the particles have a particle size of 50 to 150 nm; the particles have a specific surface area of 2 to 200 m<sup>2</sup>/g; and the abrasive has a pH of 3 to 6 or 8 to 10.

- 11. (Canceled)
- 12. (Previously Presented) An abrasive according to claim 10, wherein the additional component is a lanthanum compound.
- 13. (Previously Presented) An abrasive according to claim 10, wherein the additional component is a neodymium compound.
  - 14-18. (Canceled)
- 19. (New) An abrasive for polishing a rock crystal, a quartz glass for a photomask, a semiconductor device or a hard disk made of glass, the abrasive comprising a sol, which includes particles dispersed in an aqueous medium, wherein:

the particles comprise as a main component crystalline cerium oxide of cubic system and as an additional component a lanthanum compound, neodymium compound or a combination thereof;

the additional component is contained in an X/(Ce + X) molar ratio of 0.005 to 0.15 in which X is lanthanum atoms, neodymium atoms or a combination thereof;

the particles are present in the abrasive in an amount of 0.1 to 50 wt%; the particles have a particle size of 50 to 150 nm; the particles have a specific surface area of 2 to 200 m<sup>2</sup>/g; and the abrasive has a pH of 3 to 6 or 8 to 10.

- 20. (New) An abrasive according to claim 19, wherein the additional component is a lanthanum compound.
- 21. (New) An abrasive according to claim 19, wherein the additional component is a neodymium compound.
- 22. (New) An abrasive for polishing an organic film with the Chemical Mechanical Polishing method, an Inter Layer Dielectric (ILD), or a shallow trench isolation of a semiconductor device, the abrasive comprising a sol, which includes particles dispersed in an aqueous medium, wherein:

the particles comprise as a main component crystalline cerium oxide of cubic system and as an additional component a lanthanum compound, neodymium compound or a combination thereof;

the additional component is contained in an X/(Ce + X) molar ratio of 0.005 to 0.15 in which X is lanthanum atoms, neodymium atoms or a combination thereof;

the particles are present in the abrasive in an amount of 0.1 to 50 wt%; the particles have a particle size of 50 to 150 nm; the particles have a specific surface area of 2 to 200 m<sup>2</sup>/g; and

the abrasive has a pH of 3 to 6 or 8 to 10.

- 23. (New) An abrasive according to claim 19, wherein the additional component is a lanthanum compound.
- 24. (New) An abrasive according to claim 19, wherein the additional component is a neodymium compound.